

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BONALLE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,816,058	11-2004	McGregor et al.	340/5.26
*	B	US-2006/0034492	02-2006	Siegel et al.	382/115
*	C	US-2005/0166062	07-2005	Sanchez-Cifuentes, Alvaro	713/186
*	D	US-2005/0100199	05-2005	Boshra, Michael	382/124
*	E	US-2005/0020304	01-2005	Shinzaki, Takashi	455/556.1
*	F	US-2004/0222803	11-2004	Tartagni, Marco	324/662
*	G	US-2004/0136573	07-2004	Sato, Hideo	382/115
*	H	US-2004/0024694	02-2004	Lawrence et al.	705/38
*	I	US-2003/0191949	10-2003	Odagawa, Akihiro	713/186
*	J	US-2003/0004881	01-2003	Shinzaki et al.	705/51
*	K	US-2002/0095588	07-2002	Shigematsu et al.	713/186
*	L	US-2006/0158434	07-2006	Zank et al.	345/168
*	M	US-2005/0251688	11-2005	Nanavati et al.	713/186

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BONALLE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0139669	06-2005	Arnouse, Michael	235/440
*	B	US-2004/0158723	08-2004	Root, David C.	713/186
*	C	US-6,104,922	08-2000	Baumann, William John	455/410
*	D	US-2006/0104485	05-2006	Miller et al.	382/115
*	E	US-2004/0165753	08-2004	Takhiri et al.	382/115
*	F	US-5,737,439	04-1998	Lapsley et al.	382/115
*	G	US-6,148,093	11-2000	McConnell et al.	382/119
*	H	US-6,934,861	08-2005	Haala, Catherine A.	726/5
*	I	US-2002/0108062	08-2002	Nakajima et al.	713/201
*	J	US-2002/0138351	09-2002	Houvener et al.	705/18
*	K	US-2004/0017934	01-2004	Kocher, Robert William	382/125
*	L	US-2005/0005172	01-2005	Haala, Catherine A.	713/202
*	M	US-2005/0102524	05-2005	Haala, Catherine A.	713/186

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0180618	08-2005	Black, Gerald R.	382/124
*	B	US-6,925,565	08-2005	Black, Gerald R.	713/186
*	C	US-2003/0159044	08-2003	Doyle et al.	713/176
*	D	US-6,257,486	07-2001	Teicher et al.	235/380
*	E	US-6,636,620	10-2003	Hoshino, Satoshi	382/124
*	F	US-2002/0043566	04-2002	Goodman et al.	235/492
*	G	US-2005/0065872	03-2005	Moebs et al.	705/038
*	H	US-6,307,956	10-2001	Black, Gerald R.	382/124
*	I	US-2002/0191816	12-2002	Maritzen et al.	382/115
*	J	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
*	K	US-2004/0158723	08-2004	Root, David C.	713/186
*	L	US-2006/0173291	08-2006	Glossop, Neil David	600/424
*	M	US-2005/0171787	08-2005	Zagami, Anthony	705/001

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/710,324	BONALLE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0236699	11-2004	Beenau et al.	705/064
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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